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Electrical Characteristics

Parameters	QT901S	QT906S	QT941S	QT957S
Output freq. range (Fo)	10Hz — 1MHz (*)	1MHz — 85MHz (**)		10Hz — 450MHz (*)
Supply voltage (Vdd)	+15Vdc ± 5%	+5Vdc ± 10%		
Frequency stability (ΔF/ΔT)	See Option codes			
Operating temp. (Topr)	See Option codes			
Storage temp. (Tsto)	-62°C to + 125°C			
Operating supply current (Idd)	20mA max.	40mA max. 20mA typ. at 25MHz 30mA typ. at 50MHz		60mA max. 40mA typ. at 175MHz
Output amplitude or power	1V RMS min. 2V RMS typ.	0dBm min. +5dBm typ.		1V p-p min. for Fo < 1MHz 0dBm min. for F ≥1MHz
Output Load	1kΩ	50Ω Internally AC coupled		1kΩ for Fo < 1MHz 50Ω for Fo ≥ 1MHz
Total Harmonic Distortion (THD) or harmonics	5% max.	-20dBc max.		
Sub-harmonics	-30dBc max.			
Start-up time	10ms max.			
Phase Noise at 25°C (typ.) at:	10Hz		-70dBc/Hz	
	100Hz		-100dBc/Hz	
	1kHz		-125dBc/Hz	
	10kHz		-140dBc/Hz	
	100kHz		-145dBc/Hz	
Integrated Phase Jitter RMS (12kHz to 20MHz) typ.	1ps			
Aging (at 70°C)	± 5ppm max. first year / ± 2ppm typ. per year thereafter			

(*) Frequencies less than 500Hz require an external 1 μ F AC coupling capacitor at the output pin.

(**) Higher frequencies are available with a Q-Tech custom part number.

Other Design and Test Options

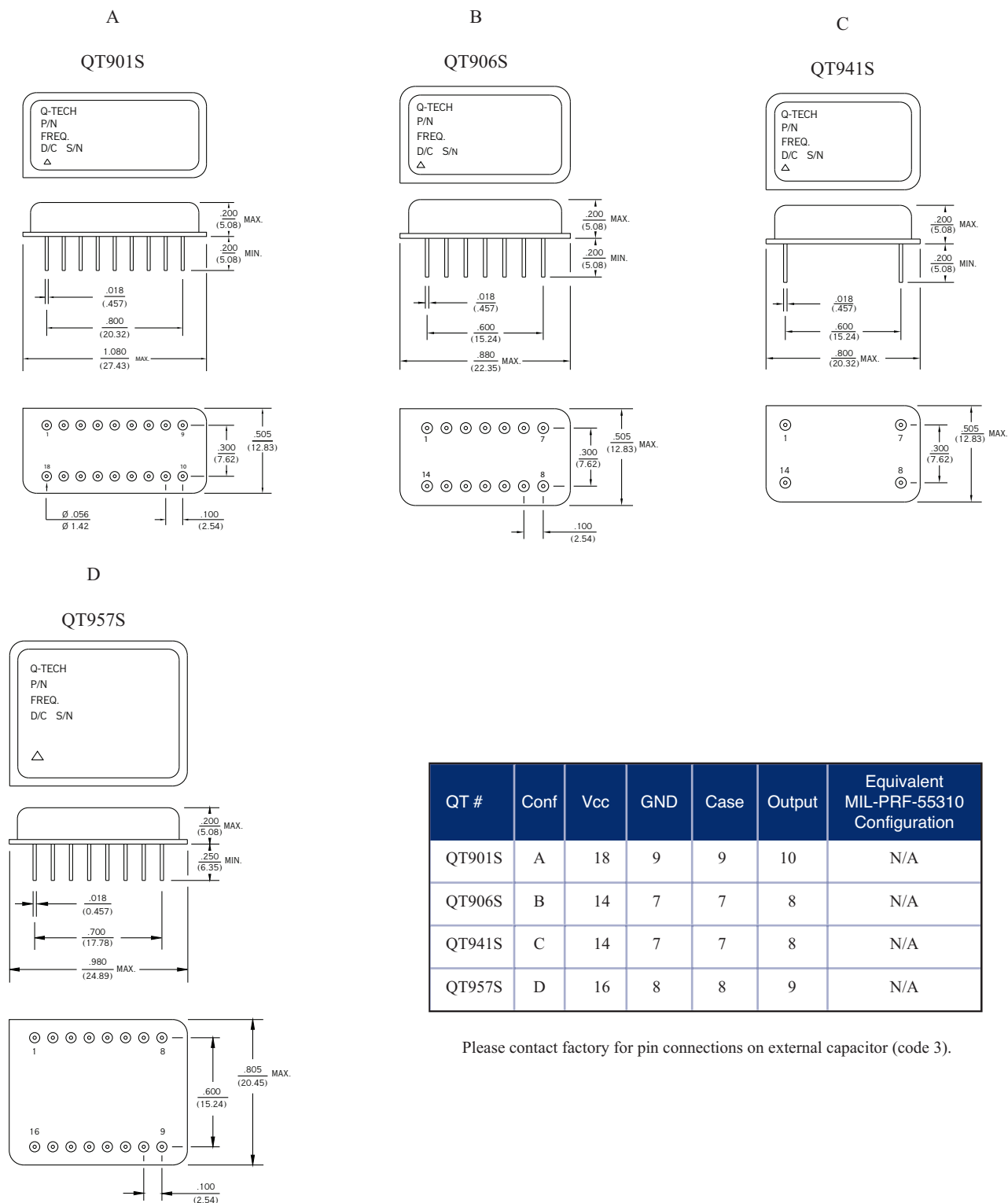
Sine Wave options are available with a Q-Tech MCM part number:

- Supply voltage +5Vdc to +18Vdc
- Output power -10dBm to +13dBm into 50 Ω (see note 1)
- Harmonics better than -20dBc (see note 2)
- Sub-harmonics better than -30dBc (see note 3)
- Amplitude stability versus temperature to within $\pm$ 1% (see note 4)
- VCXO Sine Output (see details in VCXO data sheets)
- Phase Noise and Jitter built to specification including static and vibration.
- Low supply current
- QCI tests
- Tight frequency stability versus temperature, supply voltage, and load variations
- Low g-sensitivity and low phase noise
- Low spurious (see note 5)
- Low Harmonic Distortion (THD < 5%)
- Low frequency aging, Allan Variance
- High-shock resistant

Notes:

1. The output level is determined by the supply voltage, load, and package size.
2. A specified harmonic level of -20dBc is easily achievable. The typical harmonics of Q-Tech Sine Wave source are better than -25dBc.
3. Sub-harmonic level is determined by frequency multiplication method, supply voltage, output power, and input current.
4. Typical amplitude stability over temperature is $\pm$ 10% or less.
5. Typical spurious level is better than -60dBc over the spectrum of 100kHz to 1GHz.

Package Configuration Versus Pin Connections

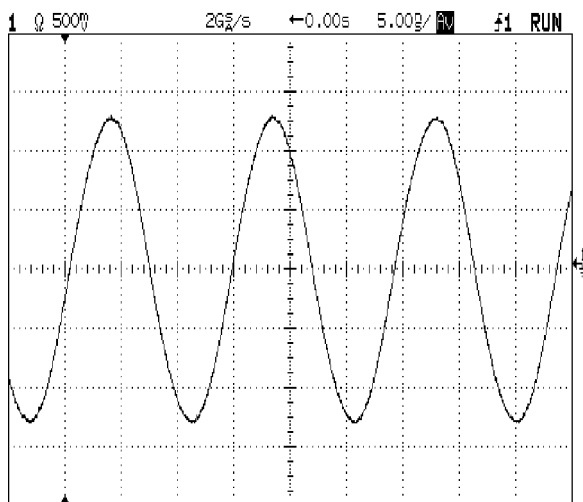


Dimensions are in inches (mm)

QT #	Conf	Vcc	GND	Case	Output	Equivalent MIL-PRF-55310 Configuration
QT901S	A	18	9	9	10	N/A
QT906S	B	14	7	7	8	N/A
QT941S	C	14	7	7	8	N/A
QT957S	D	16	8	8	9	N/A

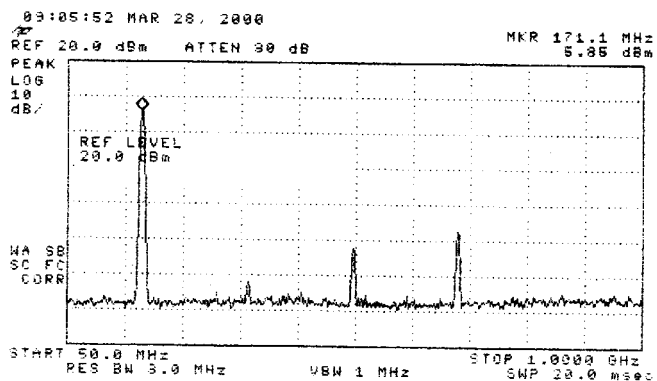
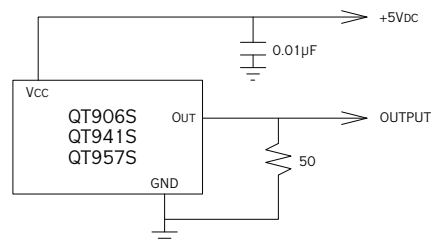
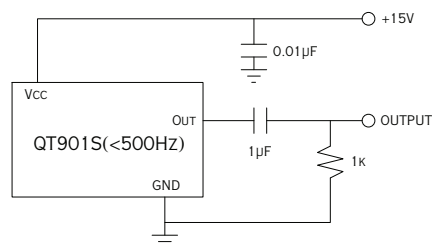
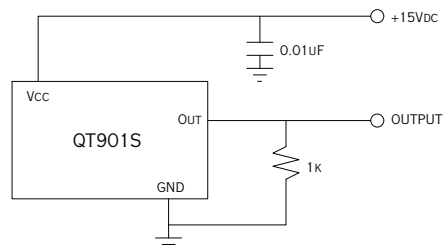
Please contact factory for pin connections on external capacitor (code 3).

Output Waveform into 50Ω load



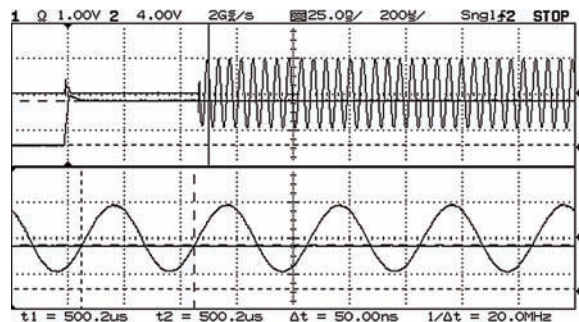
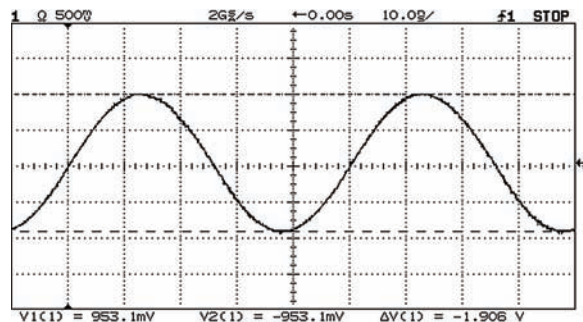
Typical output amplitude of QT957S-69.4MHz

Test Circuit



Typical spectrum output power and harmonics of QT957S-171MHz

Startup Time



Typical output amplitude and start-up time of QT957S-20.0166MHz

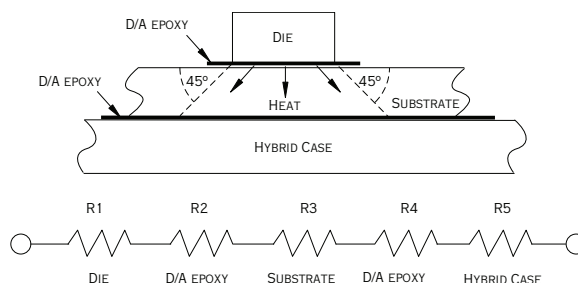
Thermal Characteristics

The heat transfer model in a hybrid package is described in figure 1 (Based on single ASIC design).

Heat spreading occurs when heat flows into a material layer of increased cross-sectional area. It is adequate to assume that spreading occurs at a 45° angle.

The total thermal resistance is calculated by summing the thermal resistances of each material in the thermal path between the device and hybrid case.

$$RT = R1 + R2 + R3 + R4 + R5$$



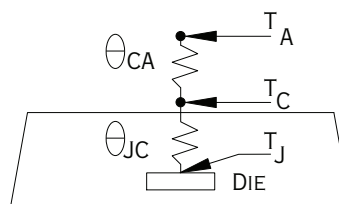
(Figure 1)

The total thermal resistance RT (see figure 2) between the heat source (die) to the hybrid case is the Theta Junction to Case (Theta JC) in °C/W.

- Theta junction to case (Theta JC) for this product is 24°C/W.
- Theta case to ambient (Theta CA) for this part is 106°C/W.
- Theta Junction to ambient (Theta JA) is 130°C/W.

Maximum power dissipation PD for this package at 25°C is:

- $PD(max) = (T_J(max) - T_A)/\theta_{JA}$
- With $T_J = 175^\circ\text{C}$ (Maximum junction temperature of die)
- $PD(max) = (175 - 25)/130 = 1.15\text{W}$



$$\theta_{JA} = \theta_{JC} + \theta_{CA}$$

(Figure 2)

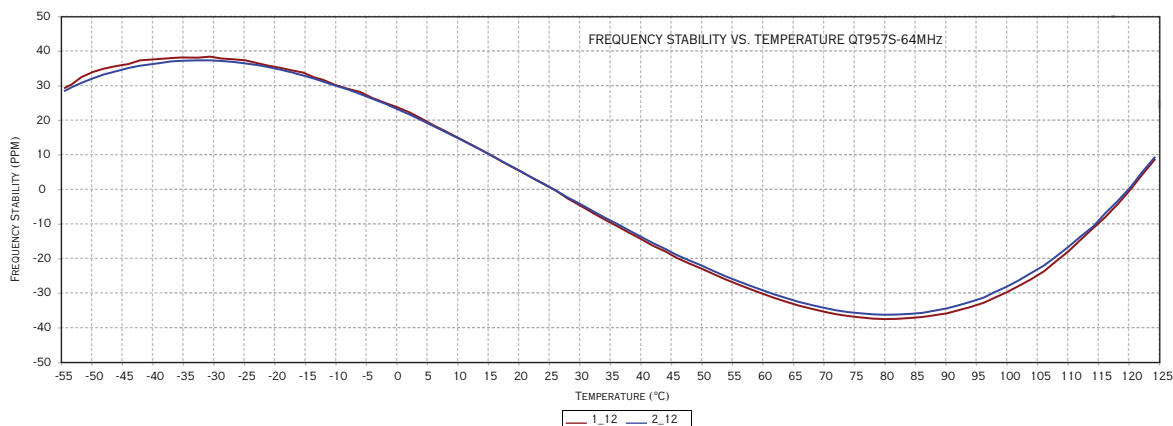
Environmental Specifications

Q-Tech Standard Screening/QCI (MIL-PRF55310) is available for all of our Sine Wave packages. Q-Tech can also customize screening and test procedures to meet your specific requirements. The Sine Wave packages are designed and processed to exceed the following test conditions:

Environmental Test	Test Conditions
Temperature cycling	MIL-STD-883, Method 1010, Cond. B
Constant acceleration	MIL-STD-883, Method 2001, Cond. A, Y1
Seal Fine Leak	MIL-STD-883, Method 1014, Cond. A
Burn-in	160 hours, 125°C with load
Aging	30 days, 70°C
Vibration sinusoidal	MIL-STD-202, Method 204, Cond. D
Shock, non operating	MIL-STD-202, Method 213, Cond. I
Thermal shock, non operating	MIL-STD-202, Method 107, Cond. B
Ambient pressure, non operating	MIL-STD-202, 105, Cond. C, 5 minutes dwell time minimum
Resistance to solder heat	MIL-STD-202, Method 210, Cond. C
Moisture resistance	MIL-STD-202, Method 106
Terminal strength	MIL-STD-202, Method 211, Cond. C
Resistance to solvents	MIL-STD-202, Method 215
Solderability	MIL-STD-202, Method 208

Please contact Q-Tech for higher shock requirements

Frequency vs. Temperature Curve



Phase Noise and Phase Jitter Integration

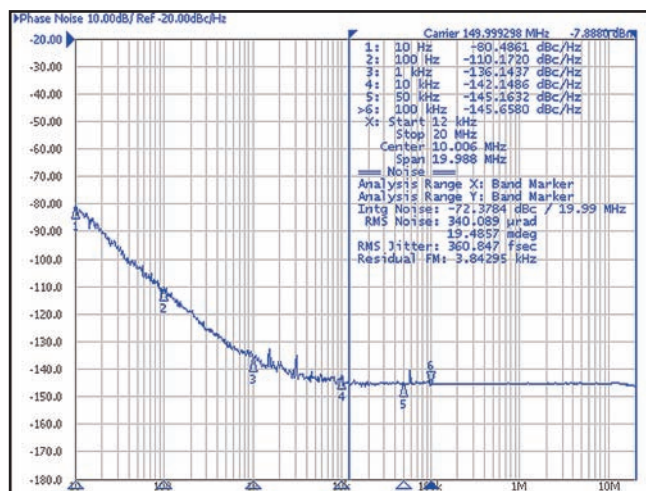
Phase noise is measured in the frequency domain, and is expressed as a ratio of signal power to noise power measured in a 1Hz bandwidth at an offset frequency from the carrier, e.g. 10Hz, 100Hz, 1kHz, 10kHz, 100kHz, etc. Phase noise measurement is made with an Agilent E5052A Signal Source Analyzer (SSA) with built-in outstanding low-noise DC power supply source. The DC source is floated from the ground and isolated from external noise to ensure accuracy and repeatability.

In order to determine the total noise power over a certain frequency range (bandwidth), the time domain must be analyzed in the frequency domain, and then reconstructed in the time domain into an rms value with the unwanted frequencies excluded. This may be done by converting $L(f)$ back to $S\phi(f)$ over the bandwidth of interest, integrating and performing some calculations.

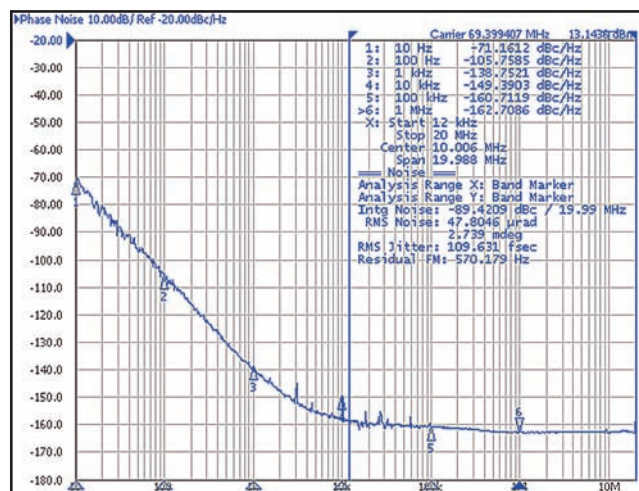
Symbol	Definition
$\int L(f)$	Integrated single side band phase noise (dBc)
$S\phi(f) = (180/\pi) \times \sqrt{2} \int L(f) df$	Spectral density of phase modulation, also known as RMS phase error (in degrees)
RMS jitter = $S\phi(f) / (f_{osc} \cdot 360^\circ)$	Jitter (in seconds) due to phase noise. Note $S\phi(f)$ in degrees.

The value of RMS jitter over the bandwidth of interest, e.g. 10kHz to 20MHz, 10Hz to 20MHz, represents 1 standard deviation of phase jitter contributed by the noise in that defined bandwidth.

Figure below shows a typical Phase Noise/Phase jitter of a QT957S, +5Vdc, 150MHz and QT957S8M, +5Vdc, 69.4MHz clock at off-set frequencies 10Hz to 10MHz, and phase jitter integrated over the bandwidth of 12kHz to 1MHz.



QT957S, +5Vdc, 150MHz



QT957S8M, 5.0Vdc, 69.4 MHz